				Complete if Known		
				Application Number	New Application	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Filing Date	March 23, 2006	
				First Named Inventor	Dieter HUHSE et al	
				Group Art Unit		
				Examiner Name		
				Confirmation No.		
Sheet	1	of	3	Attorney Docket Number	3286-103	

		U.	S. PATENT DO	OCUMENTS		
Examiner Initials*	i Number Kind Co		cument Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	
/SAT/	1.	3,445,167		Armstrong et al	5/20/69	
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Unique citation designation number: "See attached Kinds of U.S. Patent Documents. "Enter Office that issued the document, by the two-letter code.
"For Japanese patent documents, the indication of the year of the reign on the Emperor must precede the serial number of the patent document. Indication of the patent document with a foreign of the patent document with a foreign of the propriet of the patent document. And of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. "Applicant is to place a check mark here if English Inaquage translation is attached. As indicates that only an English language abstract is attached.

/Samuel A. Turner/

01/25/2008

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Sheet	2	of	3	Attorney Docket Number	3286-103	

			FOF	EIGN PA	TENT DOCUMENTS		
Examiner Initials*	Cite No.1	Office ³ Code	Foreign Patent Docum Number ⁴	ment Kind ⁵ (If known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T6
/SAT/	9.	JP	05347346		NEC Corp.	12/27/93	AE
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Sheet	3	of	3	Attorney Docket Number	3286-103	

		NON PATENT LITE	RATURE DOCUMENTS	,			
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where publisher.					
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Examiner /Samuel A. Turner/ Signature		/Samuel A. Turner/	Date Considered	01/25/2008			

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